Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : **3** Type : **not specified**

Implementation of External Ion Beam Imaging

Monday, 26 September 2016 14:00 (1:00)

Content

Beam scanning implementation (magnetic deflection + mechanical displacement) Optimization of counting statistics and dwell time/pixel Motorized X/Y/Z sample holder Safety: large view/ microscope camera with recording He gas flow Magnetic deflector (PIXE for light elements) Optimal Filters Simultaneous techniques Beam charge monitoring techniques Radiation safety with external beams: rules and procedures

Summary

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Session Classification : DAY 1